

INTERNATIONAL SEARCH REPORT

International Application No
PCT/IB2004/052145

C. (Continuation) DOCUMENTS CONSIDERED TO BE RELEVANT

Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
A	INTERNATIONAL BUSINESS MACHINES CORPORATION: "In-situ exposure tool monitor" RESEARCH DISCLOSURE, KENNETH MASON PUBLICATIONS, HAMPSHIRE, GB, vol. 426, no. 88, October 1999 (1999-10), XP007124945 ISSN: 0374-4353 figure 1	1-14
A	----- SINGH B ET AL: "IC wafer reflectivity measurement in the UV and DUV and its application for ARC characterization" PROCEEDINGS OF THE SPIE - THE INTERNATIONAL SOCIETY FOR OPTICAL ENGINEERING USA, vol. 1926, 2 March 1993 (1993-03-02), pages 151-163, XP009042684 ISSN: 0277-786X figures 3-6	1-14
A	----- GAMSKY C J ET AL: "Quantitative analysis of chemically amplified negative photoresist using mirror-backed infrared reflection absorption spectroscopy" PROCEEDINGS OF THE SPIE - THE INTERNATIONAL SOCIETY FOR OPTICAL ENGINEERING USA, vol. 2438, 20 February 1995 (1995-02-20), pages 143-152, XP009042685 ISSN: 0277-786X figure 1	1-14
A	----- US 2002/012876 A1 (HALLE SCOTT DAVID ET AL) 31 January 2002 (2002-01-31) figure 5a -----	1-14

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Box II Observations where certain claims were found unsearchable (Continuation of item 2 of first sheet)

This International Search Report has not been established in respect of certain claims under Article 17(2)(a) for the following reasons:

1. ☐ Claims Nos.:
because they relate to subject matter not required to be searched by this Authority, namely:
2. ☐ Claims Nos.:
because they relate to parts of the International Application that do not comply with the prescribed requirements to such an extent that no meaningful International Search can be carried out, specifically:
3. ☐ Claims Nos.:
because they are dependent claims and are not drafted in accordance with the second and third sentences of Rule 6.4(a).

Box III Observations where unity of invention is lacking (Continuation of item 3 of first sheet)

This International Searching Authority found multiple inventions in this international application, as follows:

see additional sheet

1. ☐ As all required additional search fees were timely paid by the applicant, this International Search Report covers all searchable claims.
2. ☐ As all searchable claims could be searched without effort justifying an additional fee, this Authority did not invite payment of any additional fee.
3. ☐ As only some of the required additional search fees were timely paid by the applicant, this International Search Report covers only those claims for which fees were paid, specifically claims Nos.:
4. ☒ No required additional search fees were timely paid by the applicant. Consequently, this International Search Report is restricted to the invention first mentioned in the claims; it is covered by claims Nos.:

see annex

Remark on Protest

- ☐ The additional search fees were accompanied by the applicant's protest.
- ☐ No protest accompanied the payment of additional search fees.

FURTHER INFORMATION CONTINUED FROM PCT/ISA/ 210

This International Searching Authority found multiple (groups of) inventions in this international application, as follows:

1. claims: 1-14

Methods for determining the relative swing curve amplitudes for a plurality of wafer processes in which reflectances as a function of wavelength of different photoresist coated wafers are compared.

2. claim: Claim 15

A plurality of wafers coated by different processes which have been exposed to actinic radiation.

INTERNATIONAL SEARCH REPORT

Information on patent family members

International Application No

PCT/IB2004/052145

Patent document cited in search report		Publication date	Patent family member(s)	Publication date
US 4308586	A	29-12-1981	NONE	
EP 0727715	A	21-08-1996	US 5607800 A EP 0727715 A1 JP 8255751 A	04-03-1997 21-08-1996 01-10-1996
EP 0973068	A	19-01-2000	EP 0973068 A2 JP 2000223413 A US 2002171828 A1 US 6424417 B1	19-01-2000 11-08-2000 21-11-2002 23-07-2002
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